Special Issue

Deep Learning in Medical Image Process

Message from the Guest Editors

Recently, deep learning has shown its power to successfully help to identify, classify, segment, reconstruct, and quantify patterns in images. Many deep learning models have been applied to identify abnormalities and highlight conspicuous parts in medical images. Meanwhile, deep learning models are used for reconstruction, denoising, and enhancement quality of medical images. Deep learning technologies are the power tools that facilitate physicians in diagnosing diseases through medical images in clinical environments. The purpose of this Special Issue "Deep Learning in Medical Image Process" is to present and highlight novel algorithms, architectures, techniques, and applications of deep learning for medical image processes. This Special Issue welcomes contributions from all aspects of the recent research and development related to medical image processing that include, but not limited to:

- machine learning
- deep learning
- transfer learning
- medical image
- computer-aided
- explainable Al

Guest Editors

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Deadline for manuscript submissions

closed (31 January 2023)



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About the Journal

Message from the Editor-in-Chief

Electronics is a multidisciplinary journal designed to appeal to a diverse audience of research scientists, practitioners, and developers in academia and industry. The journal is devoted to fast publication of latest technological breakthroughs, cutting-edge developments, and timely reviews of current and emerging technologies related to the broad field of electronics. Experimental and theoretical results are published as regular peer-reviewed articles or as articles within Special Issues guest-edited by leading experts in selected topics of interest.

Editor-in-Chief

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